Application of SPARC Data Analysis Tool to Benchmark PITZ Data

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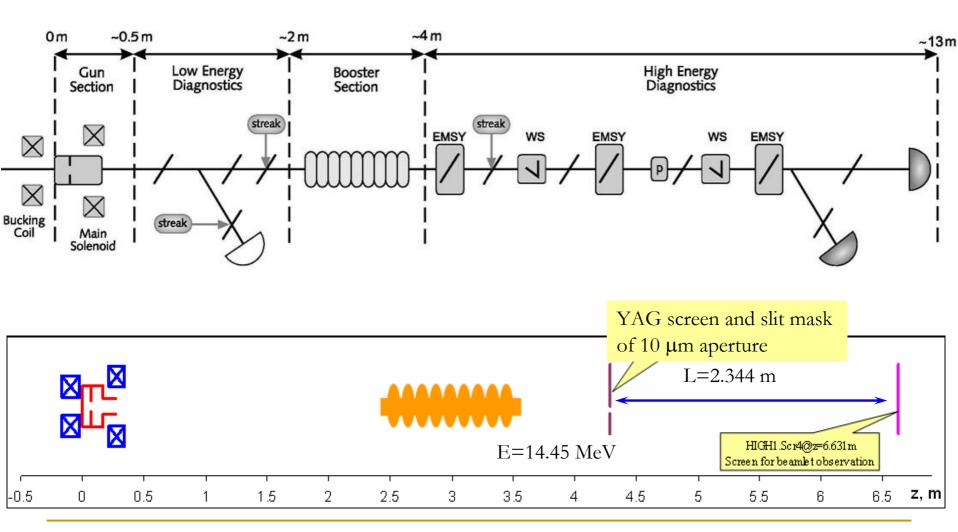
Mini Workshop on
"Characterization of High Brightness Beams"
DESY-Zeuthen,
May 26-30, 2008



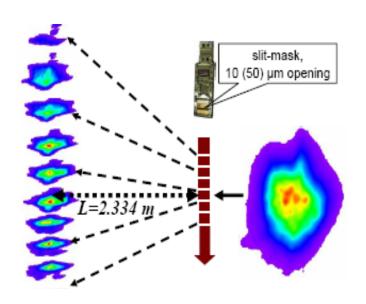
Outline

- Application of the SPARC tool to PITZ experimental setup
- Vertical and horizontal emittance analysis results
- Comparison with PITZ results
- Conclusions

PITZ Layout



Emittance Measurement Setup



Single slit scan technique

- 11 equidistant beamlets over the full beam size
- 10 μm slit aperture
- **B-scan @ fixed position**: 6 emittance measurements (in both planes) VS main solenoid current and a detailed slit scan in the waist
- At each signal measurement corresponds a background measurement

Profile Filtering

■ Minimum area of beamlets increased
 (8 bit SPARC images → 16 bit PITZ images)

 Choice of ROI beamlet sigma: guess value of the Gaussian fit decreased to be adapted to the typical PITZ beam divergence

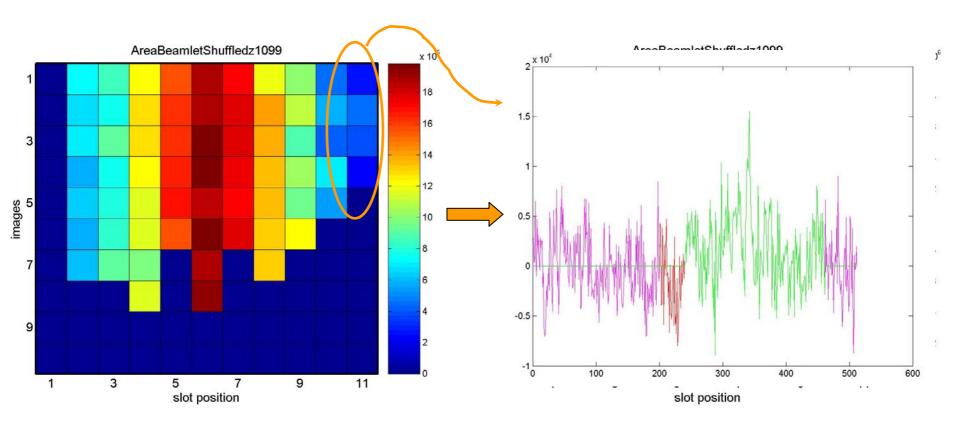
Image Selection

Use of footprint to study the effect of thresholds

 Single image correction: look for "noise-dominated" beamlets

Average image correction: average beamlet area increased

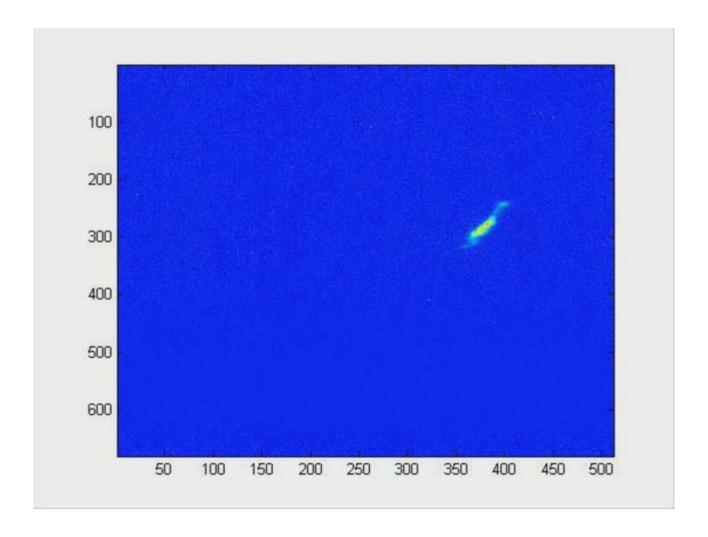
Image Selection



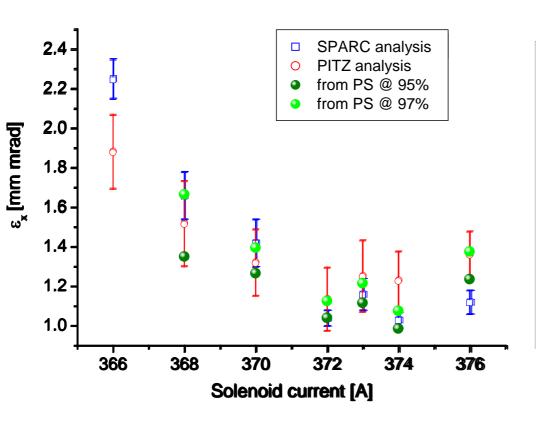
Beam Envelope @ EMSY1

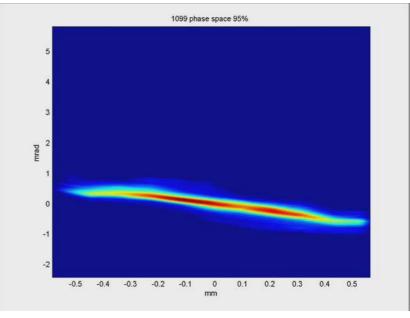


Horizontal Emittance

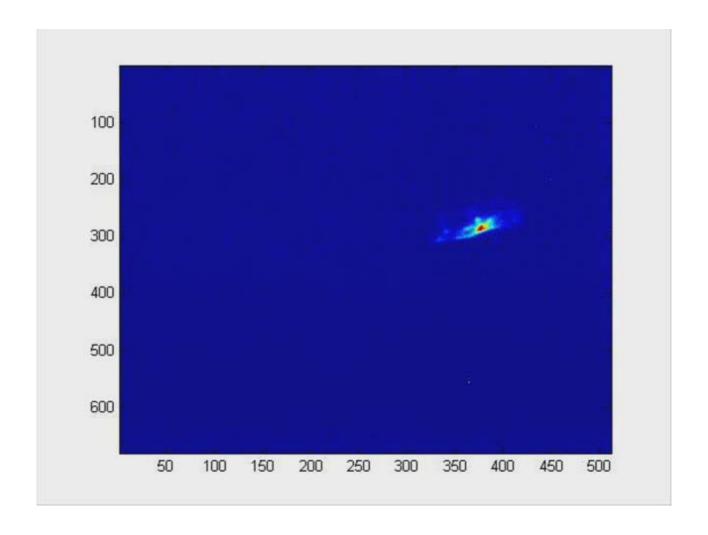


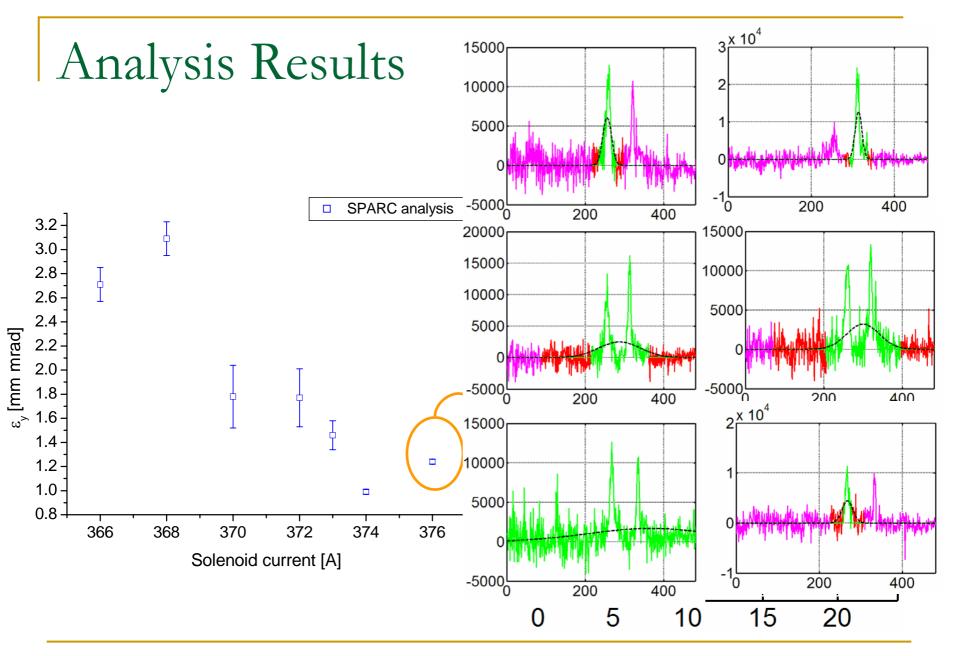
Analysis Results

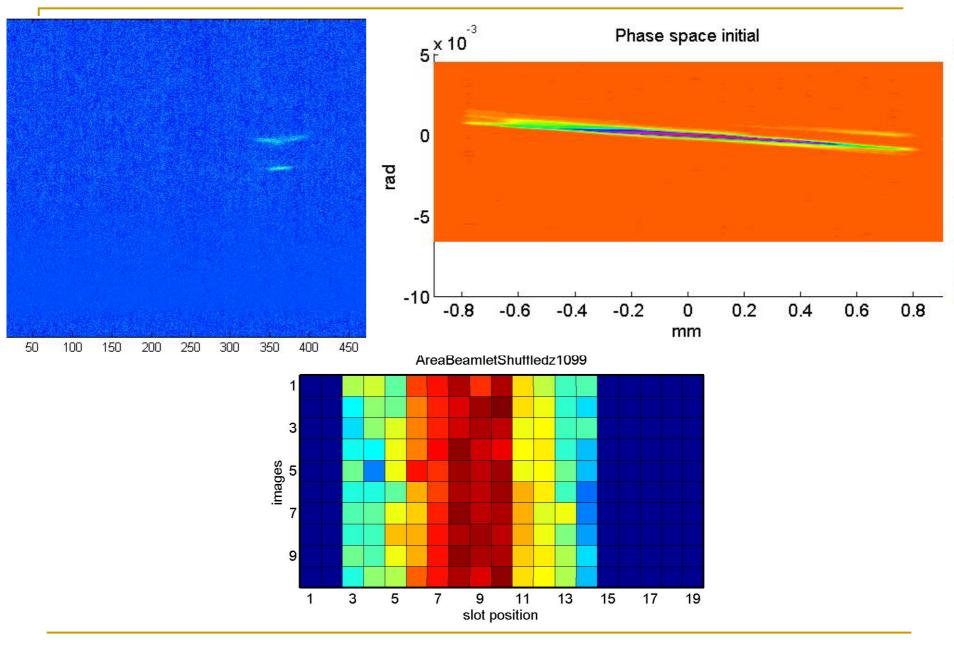




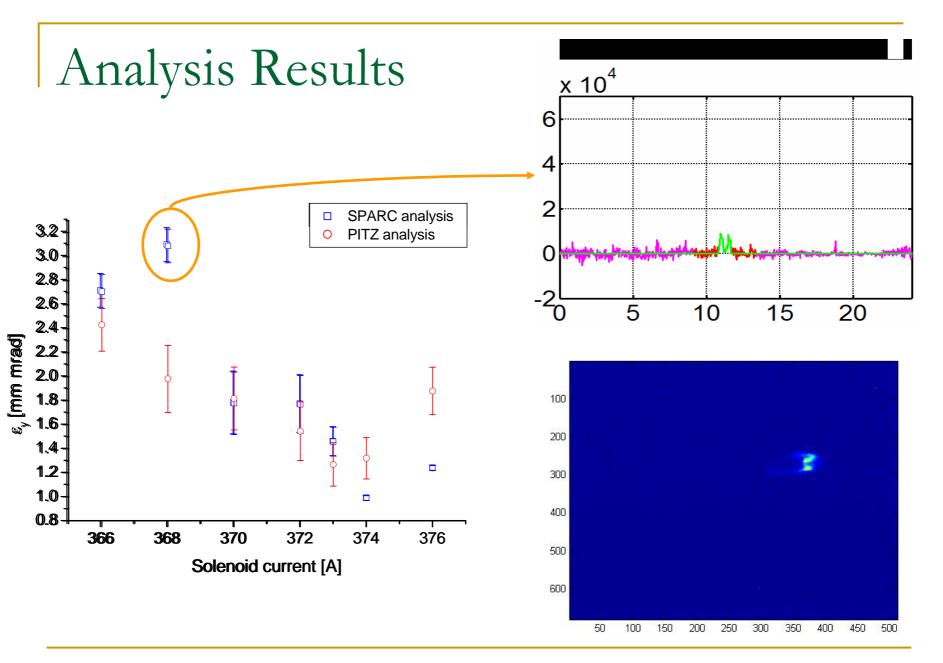
Vertical Emittance







"Characterization of High Brightness Beams" DESY-Zeuthen, May 26-30, 2008



Conclusions

- The SPARC analysis tool has been adapted to PITZ benchmark data to take into account the different experimental setup
- Even though algorithms are tailored on specific cases, the agreement has been found to be within 20% (in the worst case) and 10% (in the best case)
- Beamlets show a correlation between the two planes,
 - □ where does it come from and how do you explain it?
 - how do you treat tilted beamlets?